

G-RAD Workshop - Grenoble Radiation Testing of semiconductor devices and systems



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Facility and user relationship - Expert Panel

Thursday, 10 December 2020 14:30 (55 minutes)

This expert panel will focus on the access modes and organisational aspects of facilities. The convergence between industrial and academic needs in the use of these large-scale facilities will be addressed. Recommendations for facilitating and strengthening successful cooperation between industry (radiation testing) users and research facilities will be drawn from these discussions.

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